

Electron-Beam-Induced Fluorination Cycle for Long-Term Preservation of Graphene under Ambient Conditions

Tianbo Duan ¹, Hu Li ^{1,2} and Klaus Leifer ^{1,*}

¹ Ångström Laboratory, Department of Materials Science and Engineering, Uppsala University, 75121 Uppsala, Sweden; Tianbo.Duan@angstrom.uu.se (T.D.); Hu.Li@angstrom.uu.se (H.L.)

² Shandong Technology Centre of Nanodevices and Integration, School of Microelectronics, Shandong University, Jinan 250101, China

* Correspondence: Klaus.Leifer@angstrom.uu.se

Electronic supplementary information

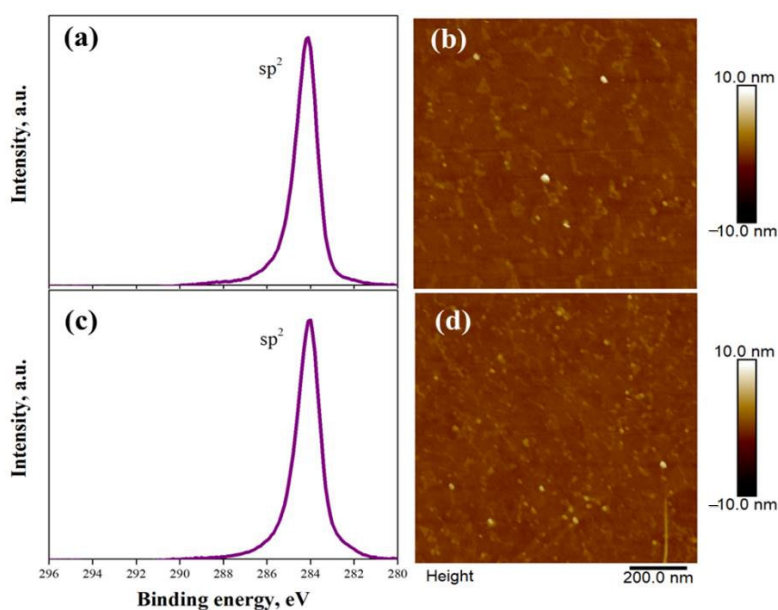


Figure S1. (a) and (c) are C1s XPS spectra of defluorinated graphene experienced the same fluorination/defluorination cycle and (b) and (d) are corresponding AFM images, respectively.

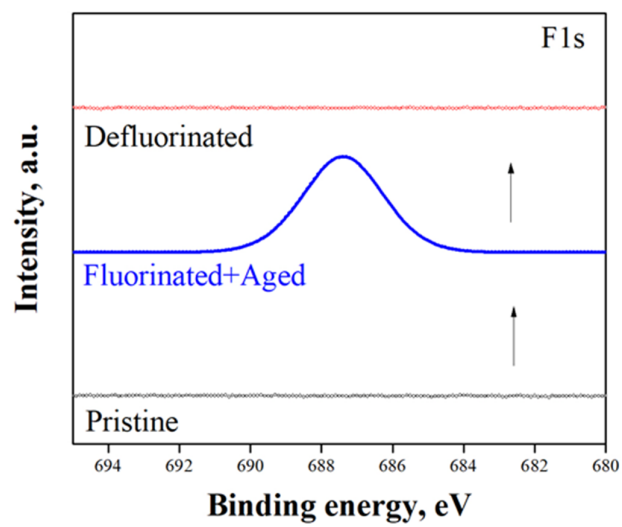


Figure S2. F1s XPS spectra of graphene sample at different fluorination/defluorination stage.